

# Large MR ratio in epitaxial $\text{Co}_{50}\text{Fe}_{50}/\text{Cu}/\text{Co}_{50}\text{Fe}_{50}$ current-in-plane giant magnetoresistive devices

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Current in-plane giant magnetoresistance (CIP-GMR) is a classical magnetoresistive effect, which had been utilized as read heads for HDD. After tunnel magnetoresistance (TMR) became major interest in spintronics, the research on CIP-GMR has become obsolete. However, CIP-GMR is worth to be revisited for a highly sensitive magnetic field sensor because of its advantages such as small low frequency noise and small bias voltage dependence of MR ratio unlike TMR devices. A serious drawback of CIP-GMR is low MR ratio compared to TMR devices, at most 29% in the trilayer device by using the specular reflection technique [1]; thus the enhancement of MR ratio will expand the possibility of CIP-GMR for various sensor applications. Although the spin-dependent scattering at the ferromagnetic layer/non-magnetic spacer interface is essential in CIP-GMR, the relationship between magnetotransport properties and interfacial microstructure in epitaxially grown CIP-GMR have not been systematically studied so far. Therefore, in this study, we fabricated epitaxial and poly-crystalline CIP-GMR devices having different crystalline orientation and interfacial lattice matching to investigate their transport property and microstructure systematically.

A multilayer stack of  $\text{Co}_{50}\text{Fe}_{50}(6)/\text{Ag}(t)$  or  $\text{Cu}(t)/\text{Co}_{50}\text{Fe}_{50}(6)/\text{IrMn}(8)/\text{Ta}(3)$  (thickness in nm) was deposited onto  $\text{MgO}(001)$  single-crystalline substrate using ultrahigh magnetron sputtering system and then annealed at  $250^\circ\text{C}$  under 3 kOe constant magnetic field to obtain the exchange bias by IrMn. The thicknesses ( $t$ ) of the Cu and Ag spacers were varied from  $t = 0 - 5$  nm. Figure 1 shows  $t$  dependence of MR ratio. As  $t$  decreases, MR ratio increases until two  $\text{Co}_{50}\text{Fe}_{50}$  layers are coupled ferromagnetically. Interestingly, the device with Cu spacer having a large lattice mismatch with  $\text{Co}_{50}\text{Fe}_{50}$  (lattice misfit  $\sim 10\%$ ) shows larger MR ratios up to 25% at room temperature compared to those with a Ag spacer with a smaller lattice mismatch with  $\text{Co}_{50}\text{Fe}_{50}$  (lattice misfit  $\sim 2\%$ ). Figure 2 shows temperature dependences of MR ratio and  $\Delta R$  of the CIP-GMR devices with Cu and Ag spacers. As temperature decreases, the MR ratio of both samples increases. On the other hand,  $\Delta R$  increases with decreasing temperature in the device with a Cu spacer while  $\Delta R$  decreases in the sample with a Ag spacer. If we assume the same spin-dependent bulk scattering in  $\text{Co}_{50}\text{Fe}_{50}$  between two samples, this result suggests a spin-dependent scattering at the  $\text{Co}_{50}\text{Fe}_{50}/\text{Cu}$  interface enlarges with decreasing temperature.

## Reference

- 1) M. Seigler, IEEE Trans. Magn., **43** (2007) 651.

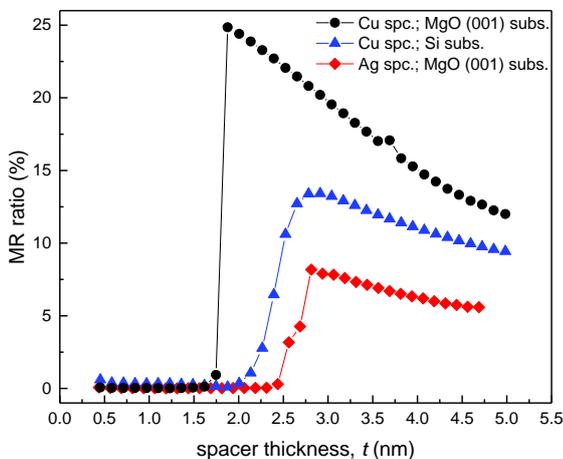


Figure 1. Spacer thickness ( $t$ ) dependence of MR ratio.

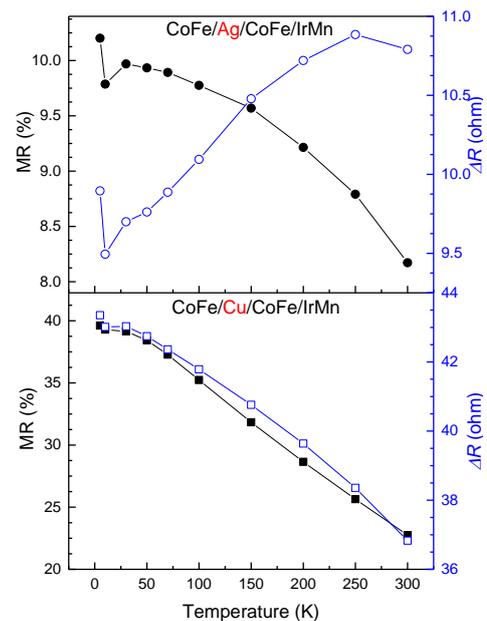


Figure 2. Temperature dependences of MR ratio and  $\Delta R$  with Ag and Cu spacers.